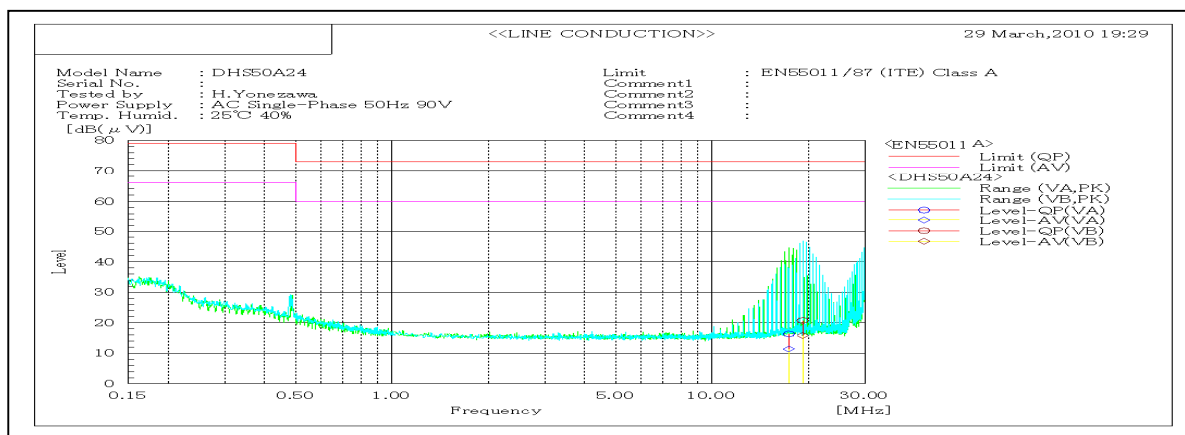
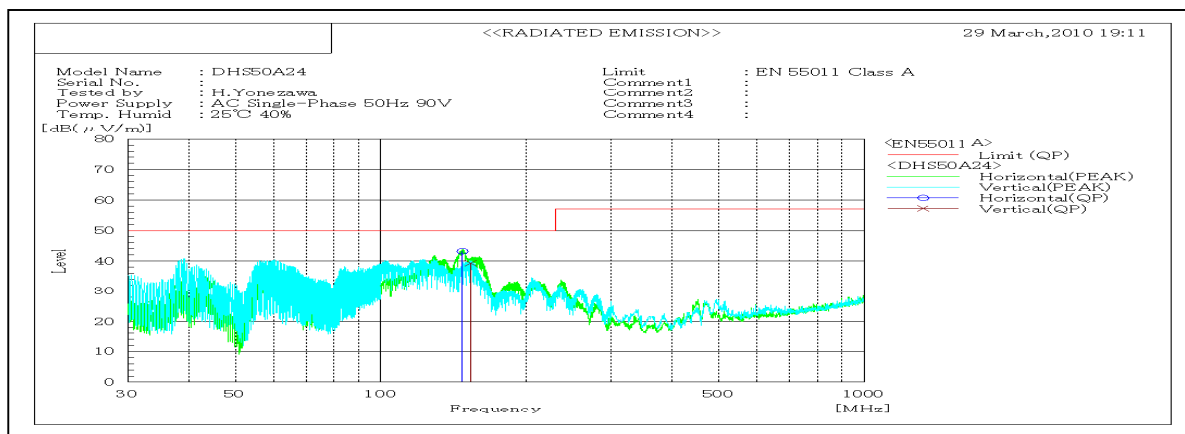


DATA SHEET		Date	26-Apr-10
Model	DHS50A24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yonezawa



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
17.3744		VA	5.5	0.6	10.8	16.3	11.4	73	60	56.7	48.6	Pass	
19.2022		VB	9.8	4.8	11	20.8	15.8	73	60	52.2	44.2	Pass	



Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB(μV)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
147.58		H		Stable	63.4			-20.2	43.2			50			6.8			Pass	160	178	
153.404		V		Stable	59.7			-20.4	39.3			50			10.7			Pass	155	183	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

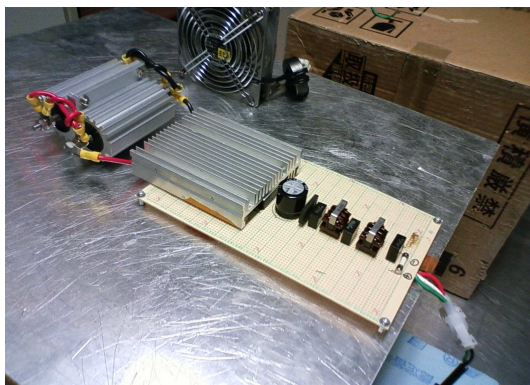


Test: EMI

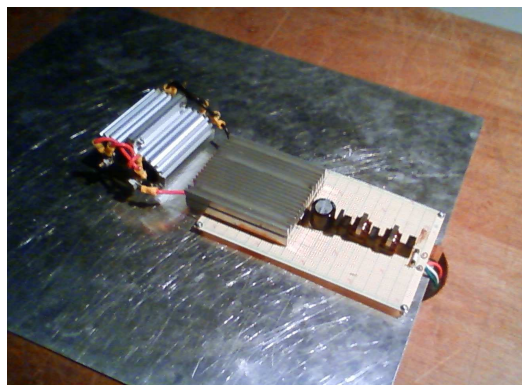
Model Name:DHS50A/DHS100A Series

○ Photographs of Test Set-Up

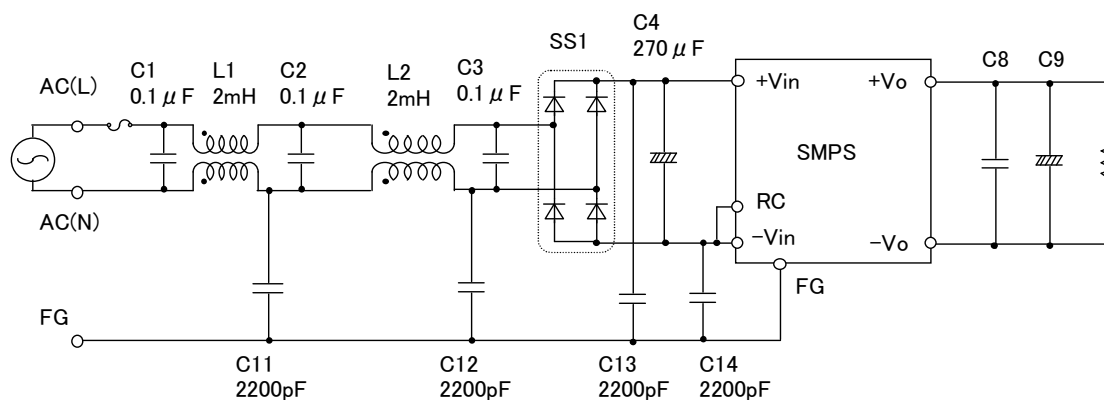
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
		Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
		DHS50A12/DHS100A12 470 μ F
		DHS50A15/DHS100A15 470 μ F
		DHS50A24/DHS100A24 220 μ F